

Search Notes

Application No.

10/696,835

Examiner

Christopher M. Keehan

Applicant(s)

WEI ET AL.

Art Unit

1712

SEARCHED

Class	Subclass	Date	Examiner
252	405	12/13/2004	CMK
	588,589		
424	70.1,70.2		
	70.6,70.7		
	70.9		
	70.11		
	70.12		
	70.22		
	70.27		
524	86,104 105		
528	342		
	335		
	332,336		
525	421		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
same as	above	12/13/2004	CMK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/13/2004	CMK
STN structure search		
Inventor name search		